

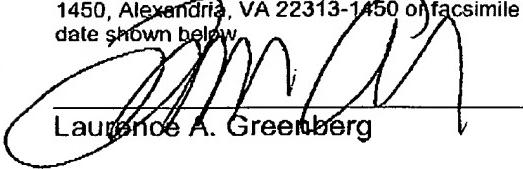
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J&R-0694

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CERTIFICATION OF MAILING OR TRANSMISSION

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 or facsimile transmitted to the U.S. Patent and Trademark Office on the date shown below.



Laurence A. Greenberg

Date

February 1, 2008

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No.	:	09/922,479	Conf. No.: 7212
Applicant	:	Thomas Zettler	
Filed	:	August 3, 2001	
Art Unit	:	2117	
Examiner	:	Phung My Chung	
Title	:	Method and Device for Testing an Integrated Circuit, Integrated Circuit to be Tested, and Wafer with a Large Number of Integrated Circuits to be Tested	
Docket No.	:	J&R-0694	
Customer No.	:	24131	

A M E N D M E N T

Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Responsive to the Office Action dated November 1, 2007 kindly amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 4 of this paper.

Amendments to the Drawings begin on page 14 of this paper and include both an attached replacement sheet and an annotated sheet showing changes.

Remarks/Arguments begin on page 15 of this paper.

An **Appendix** including 14 pages of replacements sheets and 14 pages of annotated sheets is attached following page 21 of this paper.